

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/027,488	NEEDHAM ET AL.
	Examiner	Art Unit
	Thien D. Tran	2616

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	331	4/26/2006	TT
455	442, 519	4/6/2006	TT